

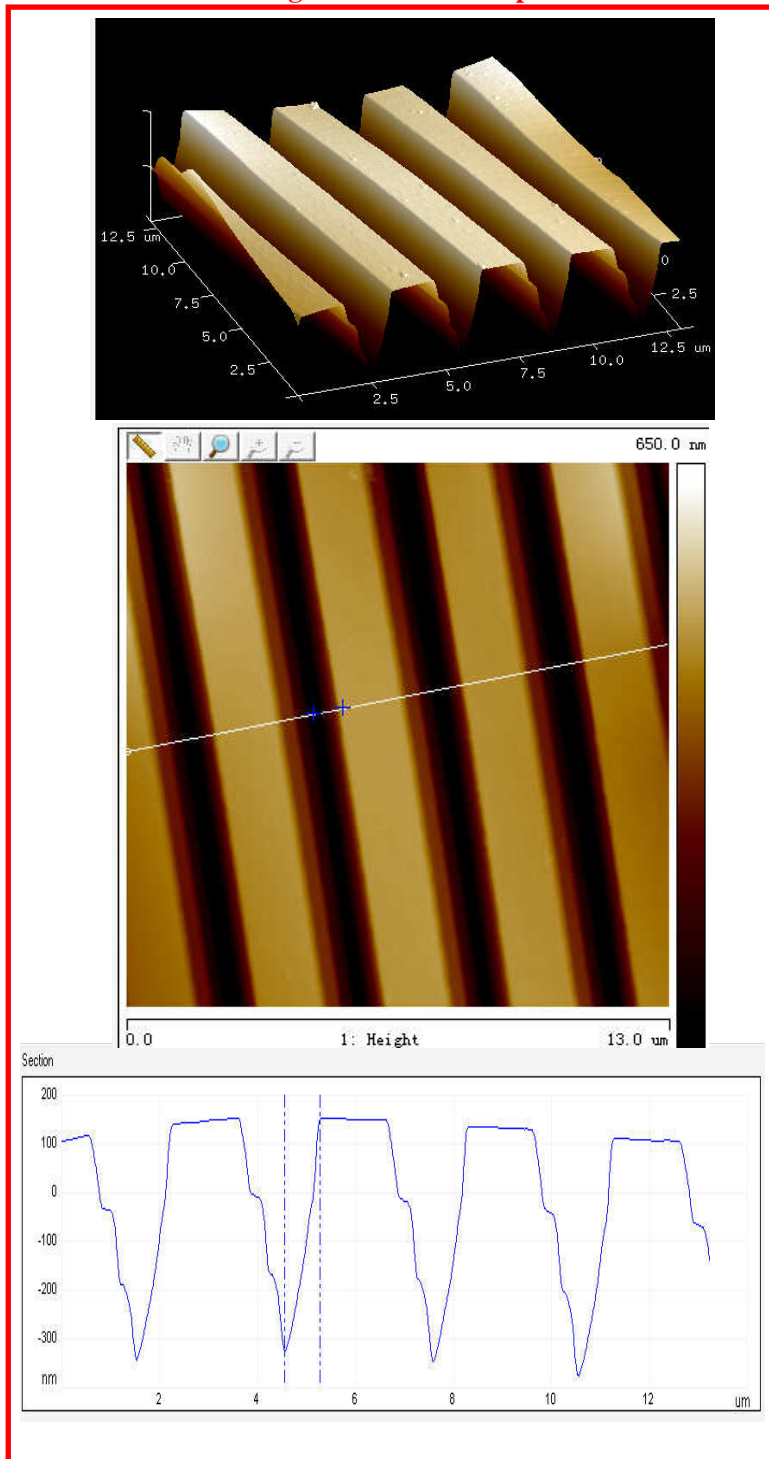
Comparison of using regular and CNT AFM probes to image on the same height calibration chip.

(1000nm height trench, HS-1, AppNano, Inc, USA)

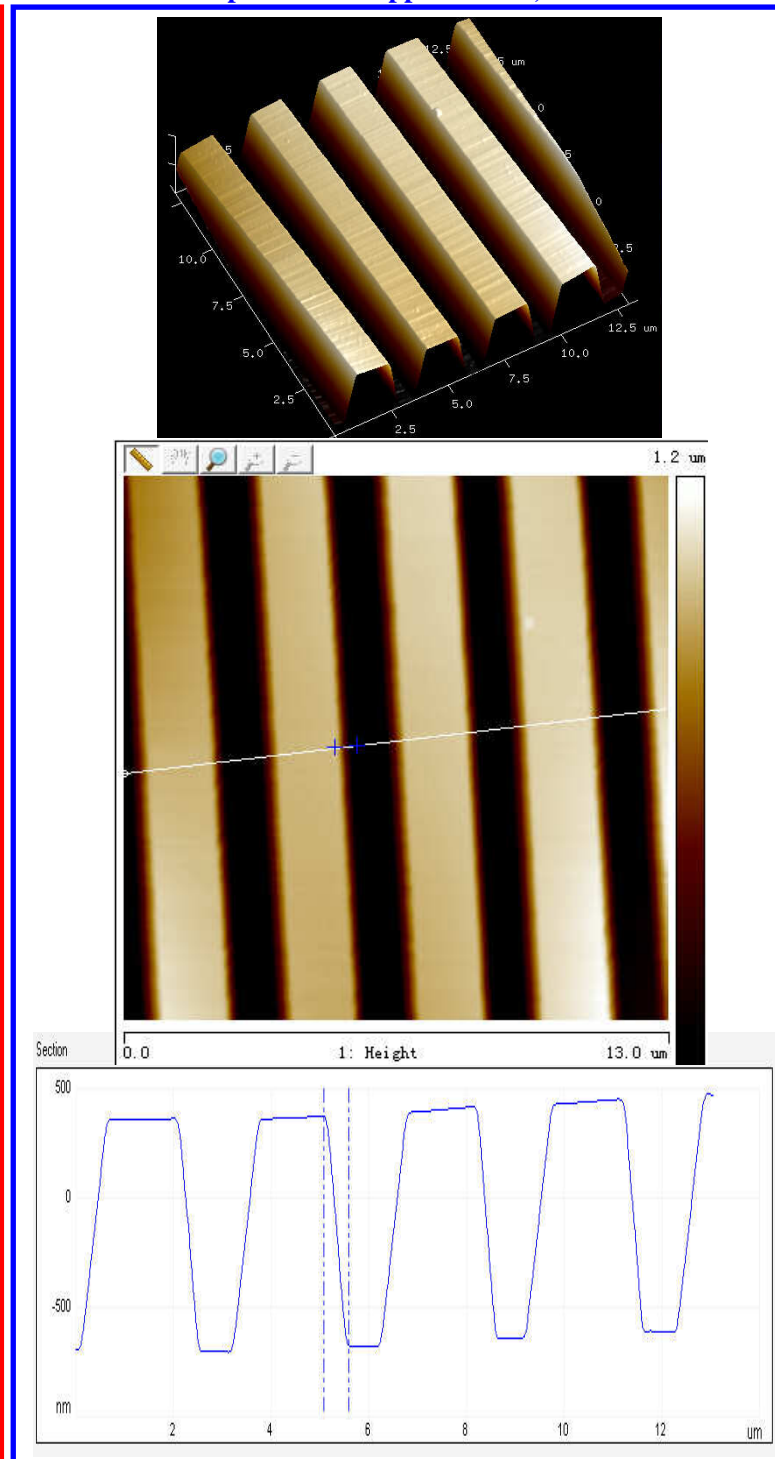
(Imaging by AFM Multimode 8, Bruker Corporation, tapping mode.)

Regular Silicon AFM probe

CNT probe from AppMaterials, Inc.



Trench height ~ 400 nm



Trench height = 1000 nm